

SiC MOSFET Module

SKM500MB120SC

Features*

- Full Silicon Carbide (SiC) power module
- High reliability 2nd Generation SiC MOSFETs
- Optimized for fast switching and lowest power losses
- High humidity robustness (HV-H3TRB proof)
- Insulated copper baseplate using DBC technology (Direct Bonded Copper)
- UL recognized, file no. E63532

Typical Applications

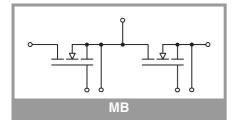
- High frequency power supplies
- · AC inverters
- Traction APU
- EV Chargers
- Industrial Test Systems

Remarks

- Case temperature limited to T_C = 125°C max.
- Recommended T_{jop} = -40 ... +150°C
- Gate-Source SURGE VOLTAGE (t_{surge}<300ns), V_{GS_surge} = -10V ... +26V

Absolute Maximum Ratings						
Symbol	Conditions		Values	Unit		
MOSFET				'		
V_{DSS}			1200	V		
I_D	T _j = 175 °C	T _c = 25 °C	485	Α		
		T _c = 80 °C	386	Α		
I _{DM}			1920	Α		
I _{DRM}			1356	Α		
V_{GS}			-6 22	V		
Tj			-40 175	°C		
Integrate	d body diode			<u> </u>		
I _{FM}			1920	Α		
I _{FRM}			1356	Α		

Absolute Maximum Ratings					
Symbol	Conditions	Values	Unit		
Module					
I _{t(RMS)}		500	Α		
T _{stg}	module without TIM	-40 125	°C		
V _{isol}	AC sinus 50 Hz, t = 1 min	4000	V		





SEMITRANS® 3

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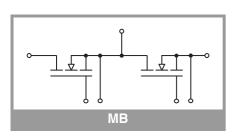
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Characte	ristics					
Symbol	Conditions	min.	typ.	max.	Unit	
MOSFET						
V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_{D} = 1 \text{ mA}, T_{i} = 25 \text{ °C}$		1200			٧
V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 106.8 \text{ mA}$		1.6		4	V
I _{DSS}	$V_{GS} = 0 \text{ V}, V_{DS} = 1200 \text{ V}, T_j = 25 ^{\circ}\text{C}$				1	mA
I _{GSS}	V _{GS} = 22 V, V _{DS} = 0 V				1200	nA
R _{DS(on)}	V _{GS} = 18 V	T _j = 25 °C		3.8	4.7	mΩ
	I _D = 264 A chiplevel	T _j = 150 °C		6.3		mΩ
C _{iss}	$V_{GS} = 0 V$	T _j = 25 °C		51.7		nF
Coss		T _j = 25 °C		1.64		nF
C _{rss}		T _j = 25 °C		0.23		nF
Q_{G}	V _{DD} =600V, V _{GS} =-5	20V, $I_D = 500 \text{ A}$		2775		nC
R _{Gint}	T _j = 25 °C			0.4		Ω
t _{d(on)}	V _{DD} = 600 V	T _j = 150 °C		83		ns
t _r	I _D = 150 A V _{GS} = -5 20 V	T _j = 150 °C		8		ns
t _{d(off)}	$R_{Gon} = 0.7 \Omega$	T _j = 150 °C		225		ns
t _f	$R_{Goff} = 0.7 \Omega$	T _j = 150 °C		40		ns
E _{on}		T _j = 150 °C		2.51		mJ
E _{off}	$di/dt_{off} = 2.7 \text{ kA/}\mu\text{s}$ $dv/dt_{off} = 19.4 \text{ kV/}$ μs	T _j = 150 °C		1.37		mJ
R _{th(j-c)}	per MOSFET				0.08	K/W
R _{th(c-s)}	per MOSFET (λ _{grease} =0.81 W/(m*K))			0.025		K/W
Integrated	d body diode					
$V_F = V_{SD}$	$-I_D = 264 \text{ A}$	T _j = 25 °C		4.10		V
	V _{GS} = 0 V chiplevel	T _j = 150 °C		3.90		V
V_{F0}	chiplevel	T _j = 25 °C		2.6		V
	Chipievei	T _j = 150 °C		2.1		V
r _F	chiplevel	T _j = 25 °C		5.7		mΩ
		T _j = 150 °C		6.8		mΩ
t _{rr}	V _{DD} = 600 V	T _j = 150 °C		56		ns
Q _{rr}	$-I_D = 150 \text{ A}$ $-di/dt_{off} = 8.4 \text{ kA/}\mu\text{s}$	T _j = 150 °C		7.2		μC
I _{rr}	$V_{GS} = -5 \text{ V}$	T _j = 150 °C		255		Α
E _{rr}	$R_{Gon} = 0.7 \Omega$	T _j = 150 °C		3.2		mJ

Characteristics						
Symbol	Conditions	min.	typ.	max.	Unit	
Module	•					•
L _{CE}				15		nΗ
R _{CC'+EE'}	measured per switch	T _C = 25 °C		0.55		mΩ
		T _C = 125 °C		0.85		mΩ
R _{th(c-s)1}	calculated without thermal coupling (\(\lambda_{\text{grease}} = 0.81 \text{ W/(m*K)}\)			0.013		K/W
R _{th(c-s)2}	including thermal coupling, T _s underneath module (\(\lambda_{\text{grease}} = 0.81 \) W/(m*K))			0.014		K/W
Ms	to heat sink M6		3		5	Nm
M _t		to terminals M6	2.5		5	Nm
	1					Nm
W					325	g

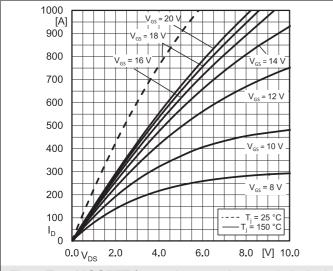


Fig.1: Typ. MOSFET forward output characteristic, incl. $R_{\text{DD}'+\,\text{SS}'}$

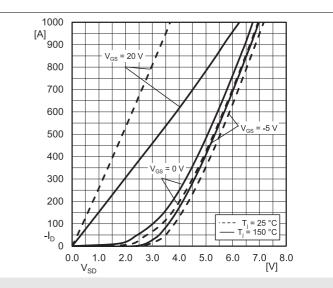


Fig. 2: Typ. reverse output characteristic, incl. R_{DD'+ SS'}

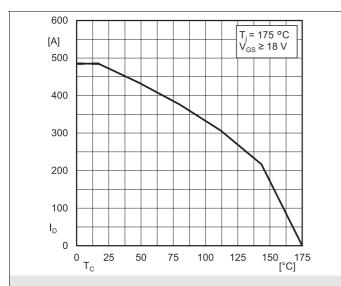


Fig. 3: Rated current vs. temperature $I_D = f(T_C)$

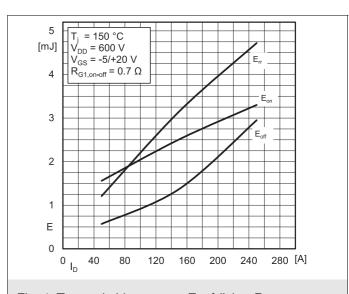


Fig. 4: Typ. switching energy $E = f(I_D)$ at R_{G1}

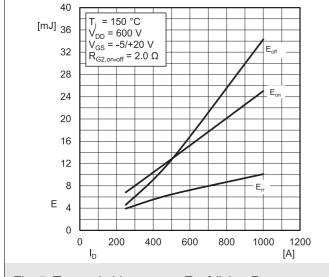


Fig. 5: Typ. switching energy $E = f(I_D)$ at R_{G2}

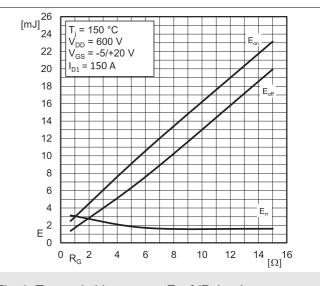


Fig. 6: Typ. switching energy $E = f(R_G)$ at I_{D1}

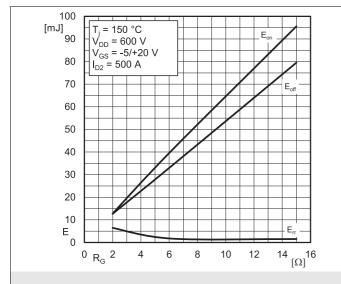


Fig. 7: Typ. switching energy $E = f(R_G)$ at I_{D2}

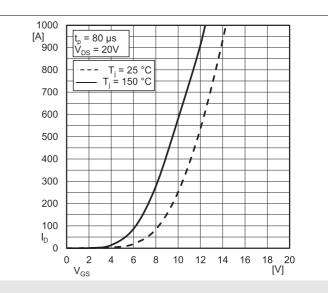


Fig. 8: Typ. MOSFET transfer characteristic

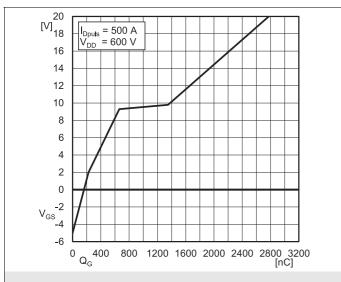


Fig. 9: Typ. gate charge characteristic

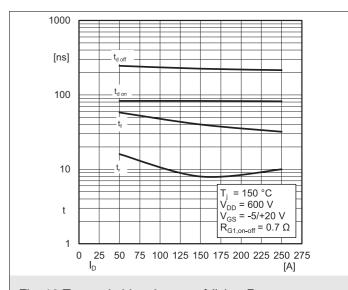


Fig. 10:Typ. switching times $t = f(I_D)$ at R_{G1}

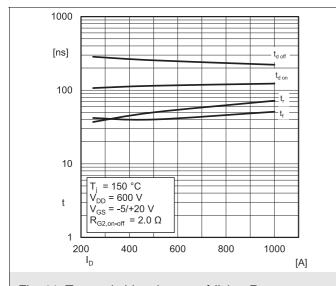


Fig. 11: Typ. switching times $t = f(I_D)$ at R_{G2}

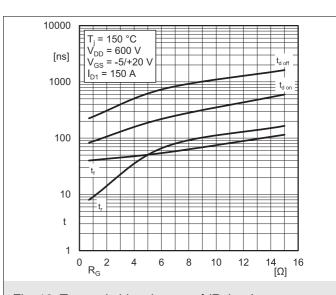
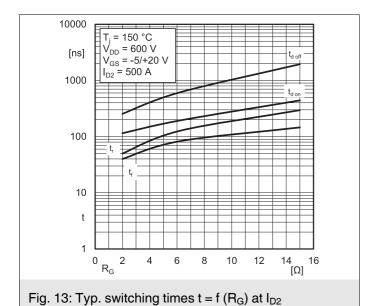
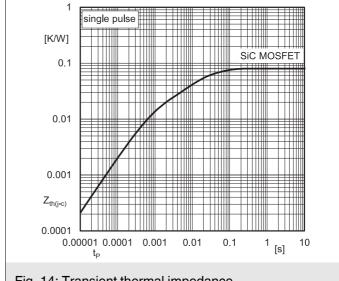
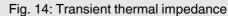


Fig. 12: Typ. switching times $t = f(R_G)$ at I_{D1}







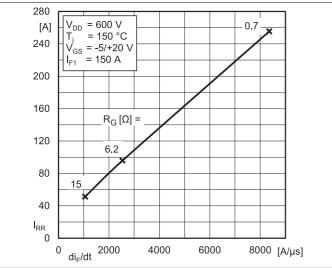


Fig. 15: Typ. diode peak reverse recovery current $I_{RR} = f (di_F/dt)$ at I_{F1} , R_G

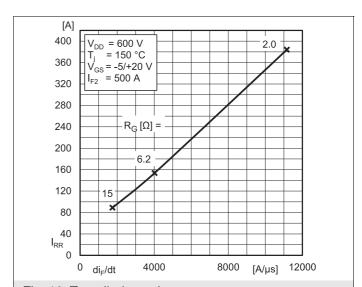


Fig. 16: Typ. diode peak reverse recovery current $I_{RR} = f (di_F/dt)$ at I_{F2} , R_G

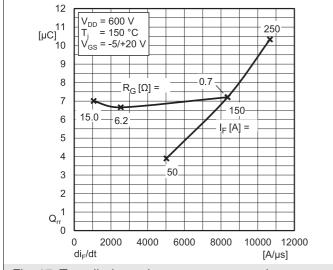


Fig. 17: Typ. diode peak reverse recovery charge $Q_{RR} = f (di_F/dt)$ at I_F , R_G

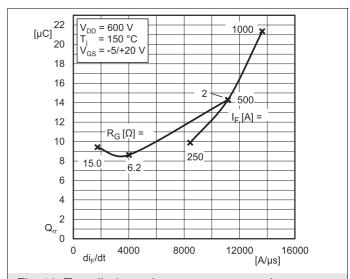


Fig. 18: Typ. diode peak reverse recovery charge $Q_{RR} = f (di_F/dt)$ at I_F , R_G

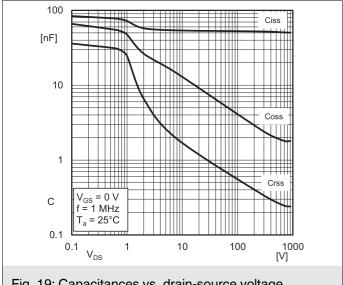
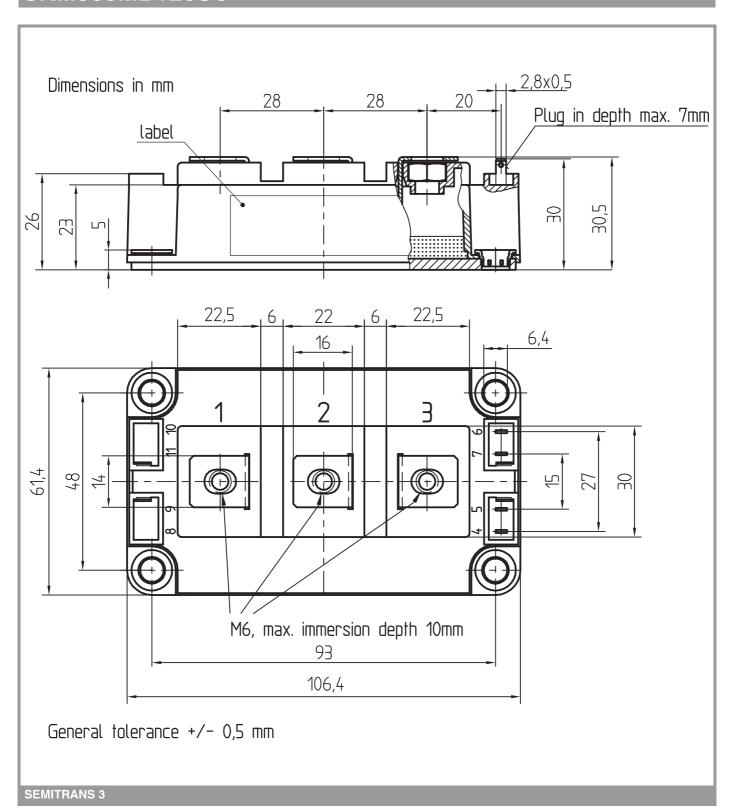
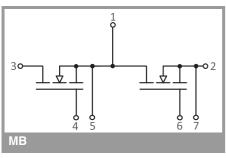


Fig. 19: Capacitances vs. drain-source voltage





This is an electrostatic discharge sensitive device (ESDS) due to international standard IEC 61340.

*IMPORTANT INFORMATION AND WARNINGS

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